

# Product/Process Change Notice - PCN 09\_0191 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Material Report). Any issues with this PCN or requirements to qualify the change (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

PCN Title: Test transfer for ADL5502 from StatsChipPac Singapore (SCS) to ASE Kaohsiung Taiwan

**Publication Date:** 11-Sep-2009

Samples Available Date:

Effectivity Date: 10-Dec-2009 (the earliest date that a customer could expect to receive changed material)

## **Description Of Change**

Analog Devices Inc. will transfer the manufacturing test process for ADL5502 from StatsChipPac to ASE Kaohsiung - Taiwan.

#### Reason For Change

The test transfer to ASE Kaohsiung is in compliance with the ADI WWMFG strategic plans and will consolidate the RF bump die in ASE Kaohsiung. Similar products like ADL5500 and ADL5504 are successfully tested in ASE Kaohsiung on the same test platform.

## Impact of the change (positive or negative) on fit, form, function & reliability

No negative impact on the fit, form, function or reliability.

## **Summary of Supporting Information**

Device correlation and lot validation testing will be performed. A report will be available after completion upon request.

Supporting Documents None

	For questions on this PCN, send email to the regional contacts below or contact your local ADI sales representative						
Americas:	PCN_Americas@analog.com	Europe:	PCN_Europe@analog.com	Japan:	PCN_Japan@analog.com		
				Rest of Asia:	PCN_ROA@analog.com		

Appendix A - Affected ADI Models  Added Parts On This Revision - Product Family / Model Number (4)						

	Appendix B - Revision History					
Rev	Publish Date	Rev Description				
Rev	11-Sep-2009	Initial Release				

Analog Devices, Inc.

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